International IOR Rectifier

IRLMS6702

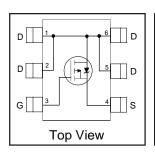
HEXFET® Power MOSFET

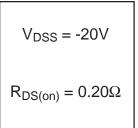
- Generation V Technology
- Micro6 Package Style
- Ultra Low R_{DS(on)}
- P-Channel MOSFET

Description

Fifth Generation HEXFET® power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET® power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The Micro6™ package with its customized leadframe produces a HEXFET® power MOSFET with $R_{DS(on)}$ 60% less than a similar size SOT-23. This package is ideal for applications where printed circuit board space is at a premium. It's unique thermal design and $R_{DS(on)}$ reduction enables a current-handling increase of nearly 300% compared to the SOT-23.







Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _A = 25°C	Continuous Drain Current, VGS @ -4.5V	-2.4	
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ -4.5V	-1.9	Α
I _{DM}	Pulsed Drain Current ①	-13	1
P _D @T _A = 25°C	Power Dissipation	1.7	W
	Linear Derating Factor	13	mW/°C
V _{GS}	Gate-to-Source Voltage	± 12	V
dv/dt	Peak Diode Recovery dv/dt ②	5.0	V/ns
T _{J,} T _{STG}	Junction and Storage Temperature Range	-55 to + 150	°C

Thermal Resistance Ratings

	Parameter	Min.	Тур.	Max	Units
$R_{\theta JA}$	Maximum Junction-to-Ambient ④			75	°C/W

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

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	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	-20			V	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.005		V/°C	Reference to 25°C, I _D = -1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.200	Ω	$V_{GS} = -4.5V, I_D = -1.6A$ ③
TOS(on)				0.375		V_{GS} = -2.7V, I_{D} = -0.80A ③
V _{GS(th)}	Gate Threshold Voltage	-0.70			V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
9 _{fs}	Forward Transconductance	1.5			S	$V_{DS} = -10V, I_{D} = -0.80A$
I	Drain-to-Source Leakage Current			-1.0		V _{DS} = -16V, V _{GS} = 0V
I _{DSS}	Dialit-to-Source Leakage Current			-25	μA	$V_{DS} = -16V$, $V_{GS} = 0V$, $T_{J} = 125$ °C
lass	Gate-to-Source Forward Leakage			-100	nA	V _{GS} = -12V
I _{GSS}	Gate-to-Source Reverse Leakage			100		V _{GS} = 12V
Qg	Total Gate Charge		5.8	8.8		I _D = -1.6A
Q _{gs}	Gate-to-Source Charge		1.8	2.6	nC	$V_{DS} = -16V$
Q _{gd}	Gate-to-Drain ("Miller") Charge		2.1	3.1		V_{GS} = -4.5V, See Fig. 6 and 9 ③
t _{d(on)}	Turn-On Delay Time		13			V _{DD} = -10V
t _r	Rise Time		20		ns	$I_D = -1.6A$
t _{d(off)}	Turn-Off Delay Time		21		115	$R_G = 6.0\Omega$
t _f	Fall Time		18			R_D = 6.1 Ω , See Fig. 10 \Im
C _{iss}	Input Capacitance		210			V _{GS} = 0V
Coss	Output Capacitance		130		pF	$V_{DS} = -15V$
C _{rss}	Reverse Transfer Capacitance		73			f = 1.0MHz, See Fig. 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions			
Is	Continuous Source Current			-1.7	4.7		MOSFET symbol		
	(Body Diode)				A	showing the			
I _{SM}	Pulsed Source Current						-13		integral reverse
	(Body Diode) ①					-13		p-n junction diode.	
V _{SD}	Diode Forward Voltage			-1.2	V	$T_J = 25$ °C, $I_S = -1.6$ A, $V_{GS} = 0$ V ③			
t _{rr}	Reverse Recovery Time		25	37	ns	T _J = 25°C, I _F = -1.6A			
Q _{rr}	Reverse RecoveryCharge		15	22	nC	di/dt = -100A/µs ③			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- T_J≤150°C
- $\textcircled{2} \ \ I_{SD} \leq \text{-1.6A, di/dt} \leq \text{-100A/}\mu\text{s, } \ V_{DD} \leq V_{(BR)DSS}, \qquad \textcircled{4} \ \ \ \text{Surface mounted on FR-4 board, } \ \ t \leq \ 5\text{sec.}$

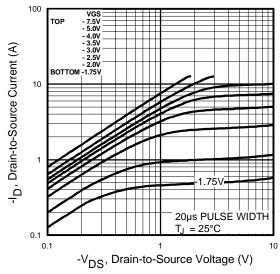


Fig 1. Typical Output Characteristics

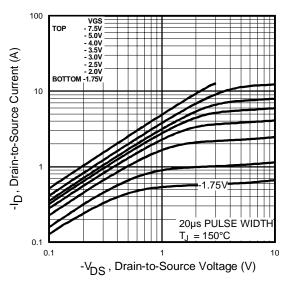


Fig 2. Typical Output Characteristics

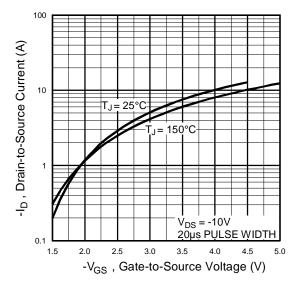


Fig 3. Typical Transfer Characteristics

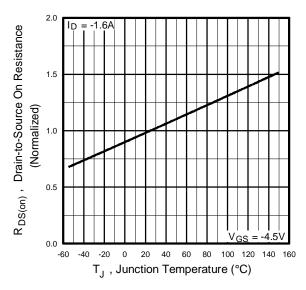


Fig 4. Normalized On-Resistance Vs. Temperature

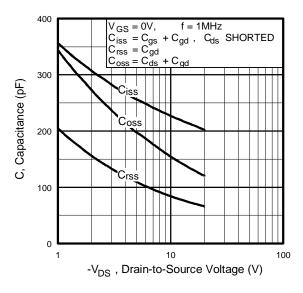


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

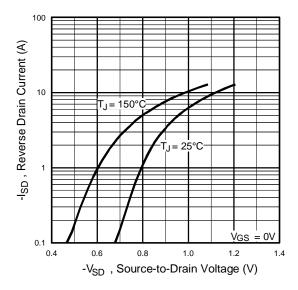


Fig 7. Typical Source-Drain Diode Forward Voltage

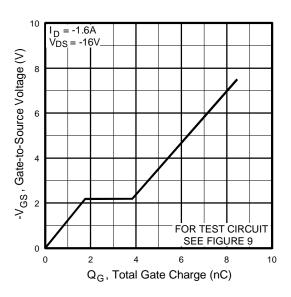


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

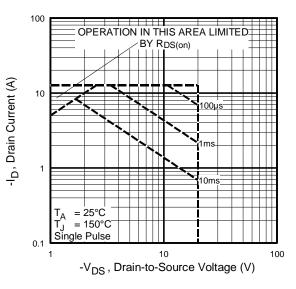


Fig 8. Maximum Safe Operating Area

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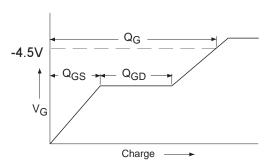


Fig 9a. Basic Gate Charge Waveform

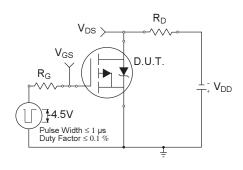


Fig 10a. Switching Time Test Circuit

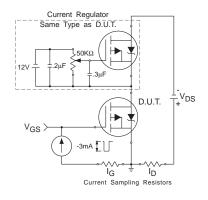


Fig 9b. Gate Charge Test Circuit

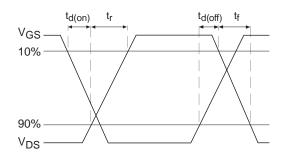


Fig 10b. Switching Time Waveforms

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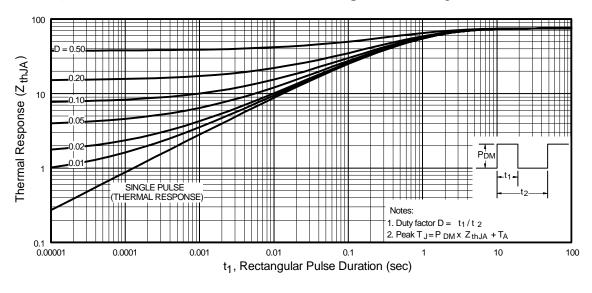
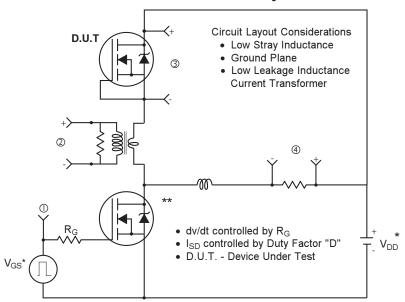


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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Peak Diode Recovery dv/dt Test Circuit



^{*} Reverse Polarity of D.U.T for P-Channel

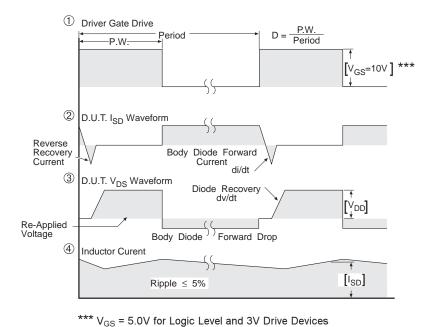


Fig 12. For P-channel HEXFET® power MOSFETs

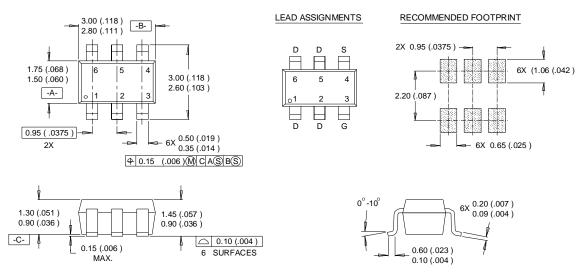
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Package Outline

Micro6™

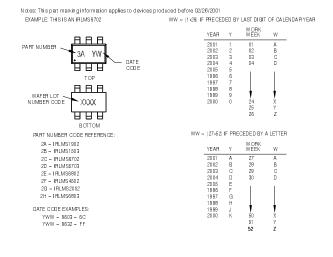


NOTES:

- 1. DIMENSIONING & TOLERANCING PER ANSI Y14.5M-1982.
- 2. CONTROLLING DIMENSION : MILLIMETER.
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).

Part Marking Information

Micro6™

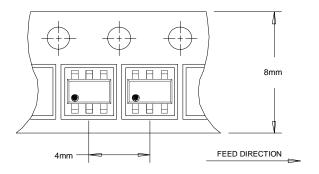


Notes: This part marking information applies to devices produced after 02/26/2001

W = |1-26| IF PRECEDED BY LAST DIGIT OF CALENDAR YEAR 2001 2002 2003 2004 2005 1996 1997 1998 1999 2000 日日日 AYW LC UU TOP PART NUMBER CODE REFERENCE: <u>A</u> = IRLM \$1902 W = |27-52| IF PRECEDED BY A LETTER B = IRLM \$1503 $\underline{D} = 1 \text{HLM } \1503 $\underline{C} = 1 \text{RLM } \6702 $\underline{D} = 1 \text{RLM } \5703 WORK WEEK YEAR E = IRLM S68022001 2002 2003 2004 2005 1996 1997 1998 1999 2000 E = IBI MS 4502 G = IRLM\$2002 $\underline{H} = IRLM S 6803$ Note: A line above the work week (as shown here) indicates Lead-Free

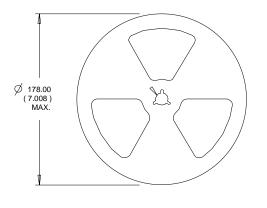
Tape & Reel Information

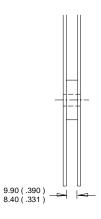
Micro6™



NOTES:

1. OUTLINE CONFORMS TO EIA-481 & EIA-541.





NOTES:

- CONTROLLING DIMENSION: MILLIMETER.
 OUTLINE CONFORMS TO EIA-481 & EIA-541.

Data and specifications subject to change without notice.



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www.datasheetcatalog.com

Datasheets for electronics components.